Notice of References Cited Application/Control No. 10/767,395 Examiner Tu M. Nguyen Applicant(s)/Patent Under Reexamination ELWART ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0193722	09-2005	Fujiwara et al.	060/285
	В	US-			
	C	US-			
	D	US-			
	Е	US-			
	F	US-			
	O	US-			
	Н	US-			
	_	US-			
	J	US-			
	Κ	US-			
	L	US-		1.0	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Ρ					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

	NON-PATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	υ							
	٧							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.